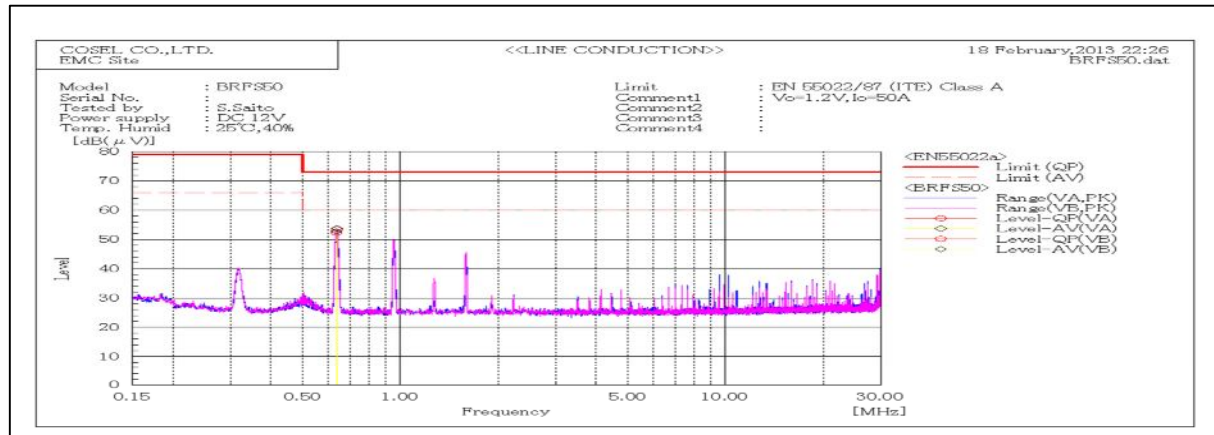
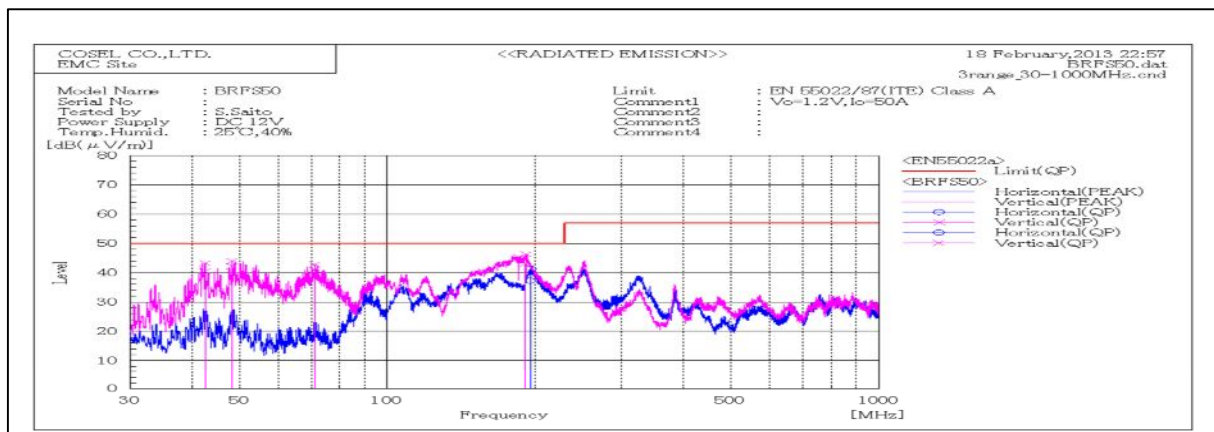


DATA SHEET

Model		BRFS50	Date	28-Mar-13
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	40 %RH
			Tested by	S.Saito



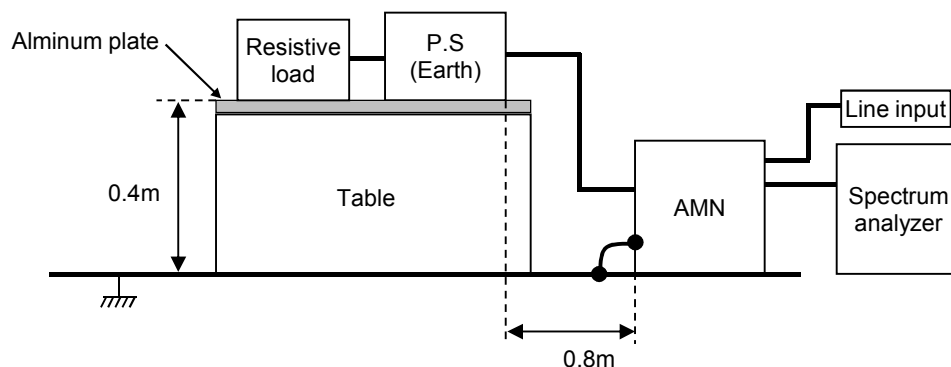
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.63637	VB	32.4	32.7	20	52.4	52.7	73	60	20.6	7.3	Pass
0.63837	VA	33.4	33.8	20	53.4	53.8	73	60	19.6	6.2	Pass



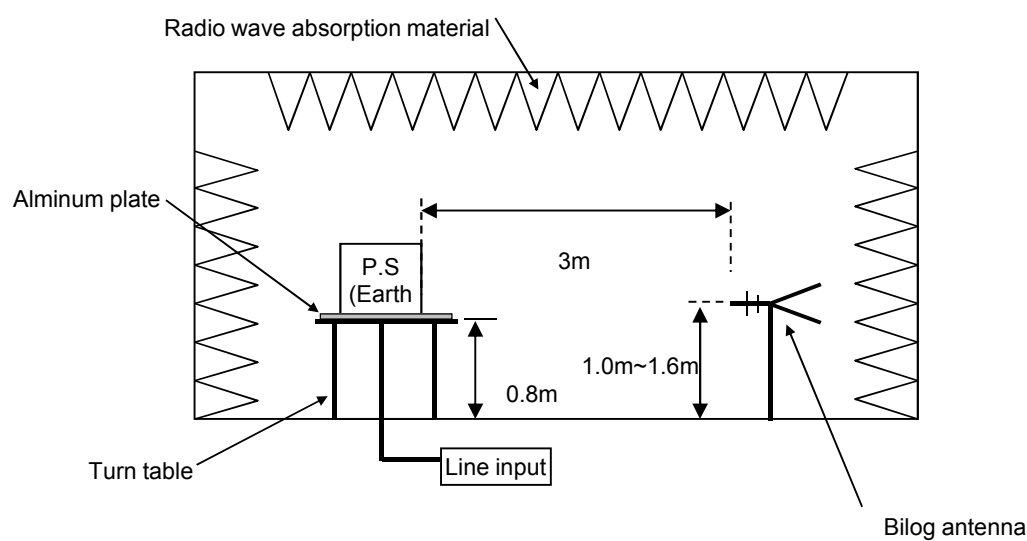
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg
			QP	AV		QP	AV					
42.546	V	Stable	57.4	-16.9	-16.9	40.5		50	9.5	Pass	103	60
48.314	V	Stable	65.4	-23.2	-23.2	42.2		50	7.8	Pass	101	130
190.98	V	Stable	58.8	-15.8	-15.8	43.0		50	7.0	Pass	103	344
195.244	H	Stable	59.6	-22.3	-22.3	37.3		50	12.7	Pass	106	123
71.129	V	Stable	61.4	-20.4	-20.4	41.0		50	9.0	Pass	128	79

DATA SHEET		Date	28-Mar-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Saito

1. Line conduction



2. Radiated emission

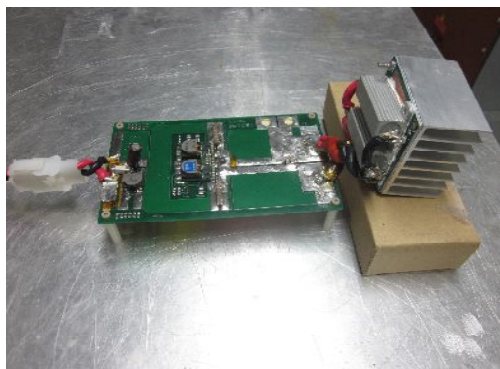


Conditions

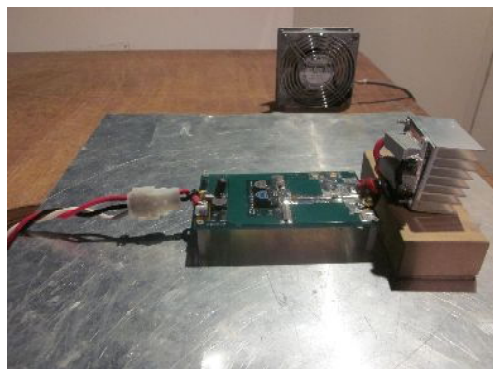
Test : EMI
Model Name : BRFS50

○Photographs of Test Set-Up

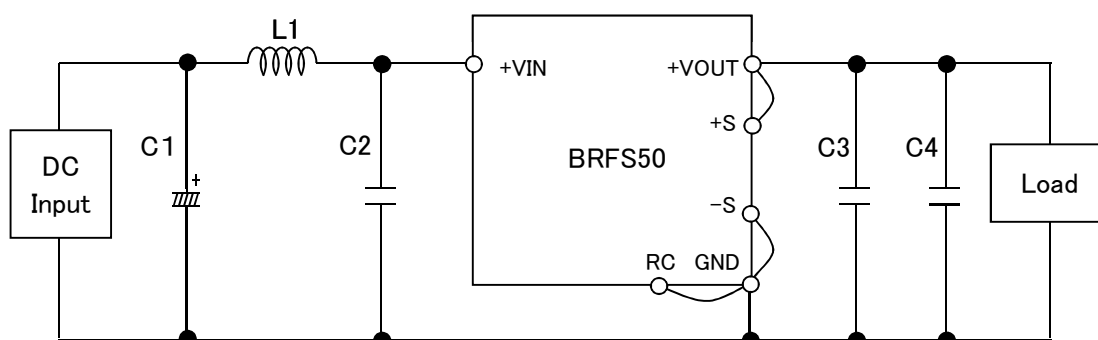
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry



C1	: 25V	220 μ F	Electrolytic capacitor
C2	: 16V	22 μ F \times 16	Ceramic capacitor
C3 ,C4	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)